

Characteristic	Symbol	Value	Units	
Drain-Source Voltage		V _{DSS}	-60	V
Gate-Source Voltage		V _{GSS}	±20	V
Continuous Prais Current (Note 5) V = 10V	T _A = +25°C T _A = +70°C	I _D	-7 -5.6	А
Continuous Drain Current (Note 5) V _{GS} = -10V	$T_C = +25^{\circ}C$ $T_C = +70^{\circ}C$	I _D	-18.2 -14.5	А
Pulsed Drain Current (10µs pulse, duty cycle = 1%)	I _{DM}	-50	Α	
Maximum Continuous Body Diode Forward Current (Note 5)	I _S	-2	Α	
Avalanche Current, L = 0.1mH	I _{AS}	-35.5	Α	
Avalanche Energy, L = 0.1mH	E _{AS}	62.9	mJ	

Thermal Characteristics (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Units	
Total Power Dissipation (Note 5)	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	P_{D}	2 1.3	W
Thermal Resistance, Junction to Ambient (Note 5)		$R_{ heta JA}$	60	°C/W
Total Power Dissipation (Note 5) $T_C = +25^{\circ}C$		P _D	17.3	W
Thermal Resistance, Junction to Case (Note 5)		$R_{ heta JC}$	7.2	°C/W
Operating and Storage Temperature Range		T _J , T _{STG}	-55 to +150	°C

Electrical Characteristics (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 6)							
Drain-Source Breakdown Voltage	BV_{DSS}	-60	_	_	V	$V_{GS} = 0V, I_D = -250\mu A$	
Zero Gate Voltage Drain Current T _J = +25°C	I _{DSS}	_	_	-1	μA	V _{DS} = -60V, V _{GS} = 0V	
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	V _{GS} = ±20V, V _{DS} = 0V	
ON CHARACTERISTICS (Note 6)							
Gate Threshold Voltage	V _{GS(th)}	-1	_	-3	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	
Static Drain-Source On-Resistance		_	_	28	mO	V _{GS} = -10V, I _D = -5A	
Static Dialit-Source Off-Resistance	R _{DS(ON)}	_	_	35		$V_{GS} = -4.5V$, $I_{D} = -4A$	
Diode Forward Voltage	V_{SD}	_	-0.7	-1.2	V	V _{GS} = 0V, I _S = -1A	
DYNAMIC CHARACTERISTICS (Note 7)							
Input Capacitance	C _{iss}	_	2569	_	pF	V 20V V 20V	
Output Capacitance	Coss	_	179	_	pF	$V_{DS} = -30V, V_{GS} = 0V,$ f = 1MHz	
Reverse Transfer Capacitance	C _{rss}	_	143	_	pF	- I - IIVIHZ	
Gate Resistance	R_g	_	8	_	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1MHz$	
Total Gate Charge (V _{GS} = -4.5V)	Qg	_	26.5	_	nC		
Total Gate Charge (V _{GS} = -10V)	Qg	_	53.1	_	nC		
Gate-Source Charge	Q _{gs}	_	7.1	_	nC	$V_{DS} = -30V, I_{D} = -5A$	
Gate-Drain Charge	Q_{gd}	_	12.6	_	nC	7	
Turn-On Delay Time	t _{D(on)}		6	_	ns	$V_{GS} = -10V, V_{DS} = -30V,$ $R_{G} = 3\Omega, I_{D} = -5A$	
Turn-On Rise Time	t _r		7.1	_	ns		
Turn-Off Delay Time	t _{D(off)}		110	_	ns		
Turn-Off Fall Time	t _f		62	_	ns		
Body Diode Reverse Recovery Time	t _{rr}		20	_	nS	I _F = -5A, di/dt = 100A/μs	
Body Diode Reverse Recovery Charge	Qrr	-	14	_	nC		

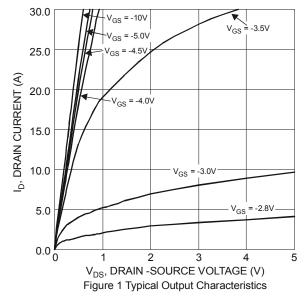
Notes: 5. Device mounted on FR-4 substrate PC board, 2oz copper, with 1-inch square pad layout.

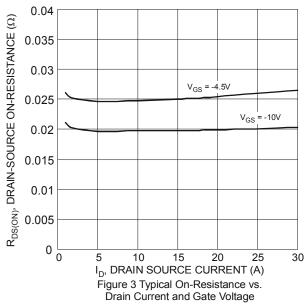
^{6.} Short duration pulse test used to minimize self-heating effect.

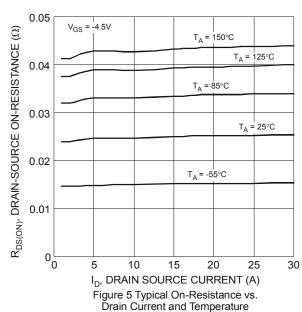
^{7.} Guaranteed by design. Not subject to product testing.

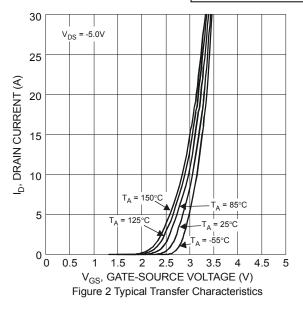


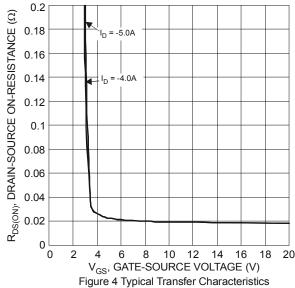












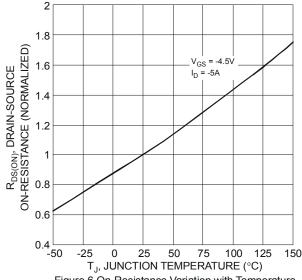
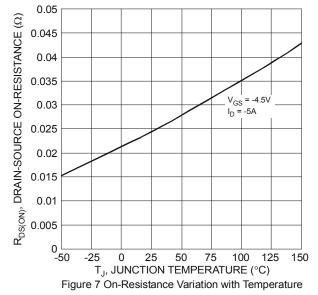
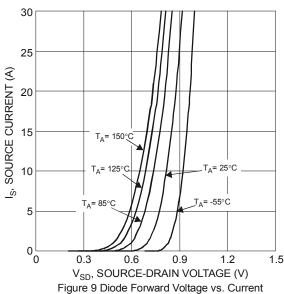
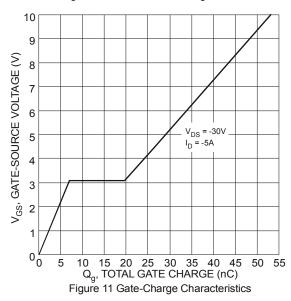


Figure 6 On-Resistance Variation with Temperature









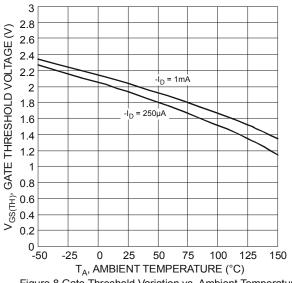
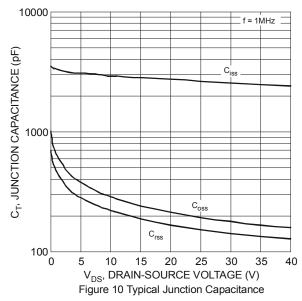
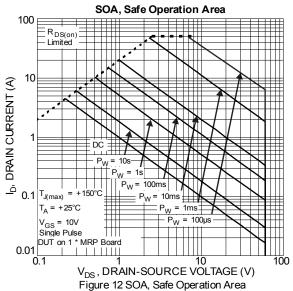
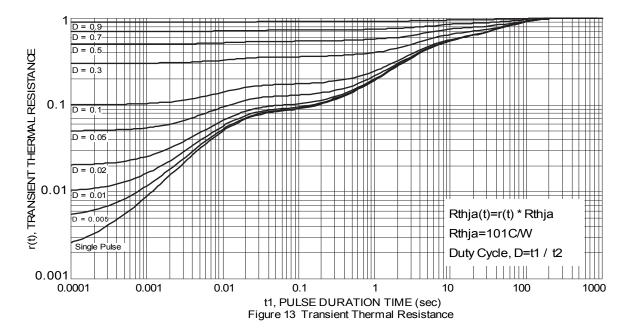


Figure 8 Gate Threshold Variation vs. Ambient Temperature





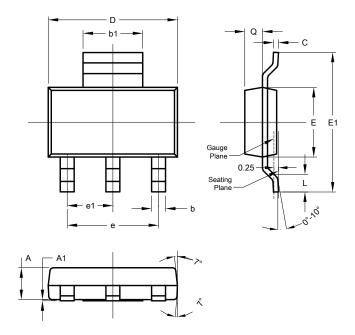






Package Outline Dimensions

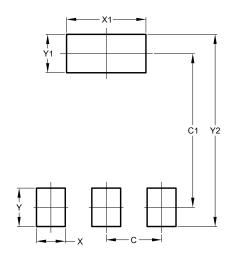
Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for the latest version.



SOT223					
Dim	Min	Max	Тур		
Α	1.55	1.65	1.60		
A1	0.010	0.15	0.05		
b	0.60	0.80	0.70		
b1	2.90	3.10	3.00		
С	0.20	0.30	0.25		
D	6.45	6.55	6.50		
E	3.45	3.55	3.50		
E1	6.90	7.10	7.00		
е	-	-	4.60		
e1	-	-	2.30		
L	0.85	1.05	0.95		
Q	0.84	0.94	0.89		
All Dimensions in mm					

Suggested Pad Layout

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)
С	2.30
C1	6.40
Х	1.20
X1	3.30
Y	1.60
Y1	1.60
V2	8 00



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